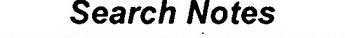


Search Notes 	Application/Control No. 10/741,824	Applicant(s)/Patent under Reexamination CHEN ET AL.
Examiner John M. Parker	Art Unit 2823	

SEARCHED

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
438	653	4/15/2007	JMP
PG Pubs search		4/15/2007	JMP